THE SIMULATION OF PREARCING CHARACTERISTICS OF FUSE ELEMENTS IN THE FINITE ELEMENT METHOD

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Abstract.

The authors use the finite element method to calculate the prearcing characteristics, theoretically explain the calculation results, compare the virtual t-I characteristic and the theoretical t-I characteristic consider the deviation very small and the method can be used in the fuse-element

1. INTRODUCTION
A lot of different methods have been developed for the simulation of prearcing characteristi-A lot of different methods have been developed for the simulation of prearcing characteristics of notched fuse elements with heavy short circuit currents, as is well known, the simulation is very successful, for example, the finite difference method (1). If the distributions of temperature and electric potential are taken into account for different shapes of notched fuse-elements, the finite element method would be more convenient because of its process of boundary conditions, fuse-element geometry and the positive stiffness matrix, that is why the f.e.m. (finite element method) is used here. After the distributions are carried out, all the parameters required can be obtained to simulate the prearcing phenomena.

2.1 <u>General discription</u>
As far as two dimensional electric current flow fields and temperature fields, general equations are:

$$\frac{\partial}{\partial x}(\mathbb{K}_{x}\frac{\partial \mathcal{O}}{\partial x}) + \frac{\partial}{\partial y}(\mathbb{K}_{y}\frac{\partial \mathcal{O}}{\partial y}) = f(x,y) + \mathbb{K}_{t}.\dot{\mathcal{O}}_{t}$$
(1)

 $\emptyset = \emptyset(x,y,t)$ t > 0, on Γ

where K_X , K_y , K_y amped coefficient, K_t damped coefficient, \emptyset potential function, 0 calculation region. boundary conditions:

$$K_{\mathbf{X}} \frac{\partial \phi}{\partial \mathbf{x}} \mathbf{n}_{\mathbf{X}} + K_{\mathbf{Y}} \frac{\partial \phi}{\partial \mathbf{y}} \mathbf{n}_{\mathbf{Y}} + \mathbf{q}(\mathbf{x}, \mathbf{y}, \mathbf{t}) = 0 \qquad \mathbf{t} > 0, \quad \text{on} \quad \Gamma_{\mathbf{Z}}$$

$$\Gamma = \Gamma_{\mathbf{1}} \cup \Gamma_{\mathbf{Z}} \qquad (2)$$

initial conditions:

$$\emptyset = \emptyset_0(\mathbf{x}, \mathbf{y}) \quad \mathbf{t} = 0, \quad \forall (\mathbf{x}, \mathbf{y}) \in \Omega \quad \dot{\emptyset} = \xi_{\epsilon}(\mathbf{x}, \mathbf{y}) \quad \mathbf{t} = 0, \quad \forall (\mathbf{x}, \mathbf{y}) \in \Omega$$
 (3)

By using the f.e.m. (2), the following equations can stem from (1),(2),(3).

Where
$$\begin{bmatrix} \mathbb{K}_{\mathbf{t}} \end{bmatrix}^{(e)} \begin{pmatrix} \mathbf{\acute{o}} \end{pmatrix}^{(e)} + \mathbb{K} \end{bmatrix}^{(e)} \begin{pmatrix} \mathbf{\acute{o}} \end{pmatrix}^{(e)} + \mathbb{K}_{\mathbf{1}}(\mathbf{t}) \end{pmatrix}^{(e)} = \begin{cases} \mathbf{0} \end{pmatrix}^{(e)} \\
\mathbb{K}_{\mathbf{t}ij} = \begin{cases} \mathbf{\acute{o}} & \mathbb{K}_{\mathbf{t}} \cdot \mathbb{N}_{\mathbf{i}} \cdot \mathbb{N}_{\mathbf{j}} & \mathrm{d}\Omega^{(e)} \\
\mathbf{\acute{o}} & \mathbb{K}_{\mathbf{i}j} = \begin{cases} \mathbf{\acute{o}} & \mathbb{K}_{\mathbf{t}} \cdot \mathbb{N}_{\mathbf{i}} \cdot \mathbb{N}_{\mathbf{j}} & \mathrm{d}\Omega^{(e)} \\
\mathbf{\acute{o}} & \mathbb{K}_{\mathbf{i}j} = \begin{cases} \mathbf{\acute{o}} & \mathbb{K}_{\mathbf{i}} \cdot \mathbb{N}_{\mathbf{i}} \cdot \mathbb{N}_{\mathbf{j}} & \mathrm{d}\Omega^{(e)} \\
\mathbf{\acute{o}} & \mathbb{K}_{\mathbf{i}j} = \begin{cases} \mathbf{\acute{o}} & \mathbb{K}_{\mathbf{i}} \cdot \mathbb{N}_{\mathbf{i}} \cdot \mathbb{N}_{\mathbf{j}} & \mathrm{d}\Omega^{(e)} \\
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\mathbf{\acute{o}} & \mathbb{K}_{\mathbf{i}j} & \mathbb{N}_{\mathbf{i}} \cdot \mathbb{N}_{\mathbf{j}} & \mathbb{N}_{\mathbf{i}} \cdot \mathbb{N}_{\mathbf{j}} & \mathrm{d}\Omega^{(e)} \\
\mathbf{\acute{o}} & \mathbb{N}_{\mathbf{i}} \cdot \mathbb{N}_{\mathbf{i}} & \mathbb{N}_{\mathbf{i}} \cdot \mathbb{N}_{\mathbf{i}} & \mathbb{N}_{\mathbf{i}} \cdot \mathbb{N}_{\mathbf{i}} & \mathbb{N}_{\mathbf{i}} \cdot \mathbb{N}_{\mathbf{i}} & \mathbb{N}_{\mathbf{i}}$$

$$R_{1i} = \int_{\Omega(e)} \mathbf{f} \cdot N_{1} \cdot d\Omega^{(e)} + \int_{\Gamma_{2}(e)} q_{1} \cdot d\Gamma_{2}^{(e)}$$

The resultant equation is
$$\left[C\right] \cdot \left\{ \phi \right\} + \left[K\right] \cdot \left\{ \phi \right\} = \left\{R(t)\right\}$$
 (4)

Where [C]. Thermal capacity matrix (or damped matrix); [K] Stiffness matrix; [R(t)] = Right hand vector. Supposing that $t_0 = t_n + e \cdot \Delta t$, $\{ \emptyset \}_0 = (\{ \emptyset \}_{n+1} - \{ \emptyset \}_n) / \Delta t$;

$$\left\{ R(t_{\Theta}) \right\} = (1-\Theta) \left\{ R(t) \right\}_{n} + \Theta \left\{ R(t) \right\}_{n+1} ; \qquad \left\{ \emptyset \right\}_{\Theta} = (1-\Theta) \left\{ \emptyset \right\}_{n} + \Theta \left\{ \emptyset \right\}_{n+1}$$

According to (4) we get

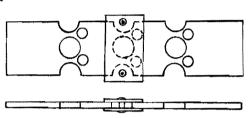
$$[C] \cdot \{ \emptyset \}_{\Theta} + [K] \{ \emptyset \}_{\Theta} = \{ R(t_{\Theta}) \}_{(5)} \text{ and } [\overline{K}] \{ \emptyset \}_{n+1} = [\overline{R}]_{n+1}$$
 (6)

where $[\overline{K}] = e[K] + 1/at \cdot [C]$; $[\overline{R}]_{n+1} = \{-(1-e)[K] + 1/at \cdot [C]\} \cdot [\emptyset]_n + (1-e) \cdot [R]_n + e[R]_{n+1} \cdot [\emptyset]_{n+1}$ is unknown array and other parameters are known, so the equation (6) is solvable.

2.2 The electric current flow field When electric currents flow through the fuse-element, the electric potential equation is stated as follows:

 $\frac{\partial}{\partial x}(\gamma \frac{\partial \phi}{\partial x}) + \frac{\partial}{\partial y}(\gamma \frac{\partial \phi}{\partial y}) = 0$

Because of the symmetry of the fuse-element as shown in Fig. 1 (A), the calculation region may be greatly simplified into Fig. 1 (B) and the current direction is taken as that of X-axis.



P(lox,loy)

Fig. 1 (A) Fuse-element

Fig. 1 (B) Calculation region

Considering the geometry of the fuse-element, Lox >R, Lox >r, in order to decrease the calculation time, supposing

 $\emptyset|_{x=0} = 0$, $\frac{100}{3x} = 10x = \frac{1}{2}$

where \mathcal{J}_0 is a constant determined by the transient current through the fuse-element. $\frac{\partial \emptyset}{\partial h} = 0$ on the other boundaries therefore the electric potential distribution satisfies the

following equation:

$$\frac{\partial}{\partial \mathbf{x}}(\mathbf{x}\frac{\partial \mathbf{x}}{\partial \mathbf{x}}) + \frac{\partial}{\partial \mathbf{y}}(\mathbf{x}\frac{\partial \mathbf{x}}{\partial \mathbf{y}}) = 0, \qquad \mathbf{x}|_{\mathbf{x}=0} = 0, \qquad \mathbf{x}\frac{\partial \mathbf{x}}{\partial \mathbf{x}}|_{\mathbf{x}=\mathbf{lox}} = \mathbf{y}_{0}$$
(7)

It is the special form of (1),(2),(3), after solving $\{\emptyset\}$, the electric strenth and the current density distribution can be gotten from $E_X = -3\emptyset/3x$, $E_Y = -3\emptyset/3y$, $\mathcal{I}_X = \hat{Y}E_X$, $\mathcal{I}_Y = \hat{Y}E_Y$. For the simplicity, is taken as only a function of the position or the local temperature, during the melting of the fuse-element, the resistance coefficient is greatly changable, it is therefore not suitable that \hat{Y} is considered not to vary with the time variable, at least, it would lead to a large model error. The heat energy produced by the current heating effect in dv at any point p(x,y) in the unit time and volume is

$$Q(IE) = ? E_{\mathbf{x}}^2 + ? E_{\mathbf{y}}^2 \tag{8}$$

2.3 The temperature field of the fuse-element The heat conduction equation (2), (3) is

$$\mathcal{C}C\frac{\partial T}{\partial t} = \frac{\partial}{\partial x}(K_{x}\frac{\partial T}{\partial x}) + \frac{\partial}{\partial y}(K_{y}\frac{\partial T}{\partial y}) + \frac{\partial}{\partial z}(K_{z}\frac{\partial T}{\partial z}) + q^{\bullet}(x,y,z,t)$$
(9)

it is difficult to precisely and directly calculate the temperature distribution of the fuseelement and its temperature field in the media (fillers), because the caps, tags and fillers surrounding the fuse-element and the surrounding temperature in the media influence on thermal fields, especially the precise thermal data of fuse fillers are lack.

In addition, there are some more problems in the calculation of long time transient fields which need to be solved, for example, the stability of solution, the velocity of convergence and the cost of calculation (cpu time), what is more, the coupled two dimensional problems with the electric field.

We start with the penetration depth to discuss how to simplify equation (9). The penetration depth of thermal fields:

 $\delta(t) = \sqrt{12} \phi_0 t \quad , \quad \phi_0 = K/6C$ (10)

where t is time variable for copper, silver, quartz and PTFE, we can get the following results:

- A. It is obvious that for small time or short circuit current, comparing $\mathcal{S}_{\mathrm{cu}}$, $\mathcal{S}_{\mathrm{Ag}}$ with \mathcal{S}_{q} neglecting \mathcal{S}_{q} can't cause large error, the range of time depends on the fuse geometry and the calculation accuracy required. In other words, within this range, three dimensional heat conduction equation can be deduce to two dimensional heat conduction equation.
- B. For medium and long time overload, we take the surfacial dissipated coefficient into acount which can be obtained from the experimental results, this item is apt to take part in the f.e.m. equations.

Another method for long time overload is to use semi-experienced formula which is based on the f.e.m. and the heat conduction theory. In case B, we must describe the item $-\int_{\Omega^{(e)}}\mathcal{M}\cdot \mathbb{N}\mathrm{id}\Omega^{(e)}$ and put it into R_{1i} . Up to now, we can get the following equations; $C\frac{\partial T}{\partial t} = \frac{\partial}{\partial x}(K_{X \partial X}^{\frac{\partial T}{\partial x}}) + \frac{\partial}{\partial Y}(K_{Y \partial Y}^{\frac{\partial T}{\partial y}}) + q^*(x.y.t)$

$$CC\frac{\partial T}{\partial t} = \frac{\partial}{\partial x} (K_{x}\frac{\partial T}{\partial x}) + \frac{\partial}{\partial Y} (K_{y}\frac{\partial T}{\partial y}) + q^{\dagger}(x.y.t)$$

$$K\frac{\partial T}{\partial n}(x,y,t) = q_{B} ; \qquad T(x,y,0) = C_{0}$$
(11)

The general calculation region is shown in Fig. 1 (B). We don't consider the conduction among the symetric sections of fuse elements. With short circuit current, $q_B=0$, that means the heat conduction doesn't exist in the element symetric lines and on the contact surfaces between fillers and the fuse-element or covered materials, if any, and the fuse element. In general, q_B depends on the surfacial state of heat discipation and $q_B \neq 0$ (related to μ), c_0 discretes the initial temperature distribution and takes a constant. We also give K_X , K_Y , C_0 C constant values respectively before the fuse-element melts.

3. PHASE CHANGE ALGORITHMS

when electric currents flow through the fuse-element, the element and the media around are heated due to Joule effect, and the temperature rises, if the energy put into the element is more than that discipated, the element temperature will go high, while the temperature is up to or above the melting point of the fuse-element, the solid-liquid phase change occurs, if it continues, maybe the liquid-gas phase change will take place.

As a basic element, the triangle element is used here, the average temperature of the local element or division element:

element or division element:

on element:
$$3$$
 $T_{ave.} = 1/3 \sum_{i=1}^{\infty} T_i, \qquad \Delta T_m = H_m/C_{ps}$ (12)

for each triangle element, when T_{ave} exceeds T_m , it should be changed to T_m , and write down $(T-T_m)$ or (T_i-T_m) . If $(T-T_m)\geqslant_a T_m$, the temperature of local element is admitted to increase in normal way, for each node, it is similar. Further more, the similar algorithm is suitable for the vaporization and M-spots.

It is hard to say shen notched elements begin to arc, because the initial arc is related to the electric current density, the fuse-element geometry, the properties of materials and so on. we suppose that arc occurs when the temperature of local element begins to rise after the melting of the local region, therefore the temperature lies in the range of $T_{\rm m}$ to $T_{\rm a}$ or more high.

The prearcing virtual time
$$t_v = \int i^2 dt / I_p^2$$
 (13)

The calculation results prove that it is true.

4. PROGRAM DEDIGIN

The diagram (see Fig. 2) shows us how to finish the simulation work in f.e.m. Fig.2(B) gives the block for CURRENT DISTRIBUTION AND TEMPERATURE DISTRIBUTION. All the programs are written in Foktran 77 running well in Dps 8/52 in COMPUTER CENTER of Xi'an Jigotong University, China.

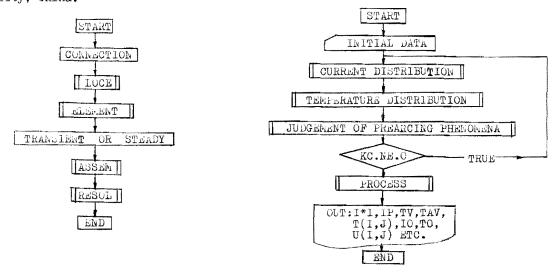


FIG. 2 (B) BLOCK DIAGRAM

FIG. 2 (A) BLOCK DIAGRAM

5. THE FURNULA FUR LOW UVERLOAD

we recommand a simi-experienced formula which is suitable for the fuse-element with M-spots and covered materials throughlow overload currents.

The virtual time
$$t_v = t_m + t_r$$
, where t_r depends on the following equations:
$$v = \frac{12}{1_c^2} \cdot T_W(1 - e^{-t_r/T}); \quad T = \frac{CCT_W}{C_e \cdot I_c^2} \cdot \frac{C_0(1 - \eta)}{C_0(1 - \eta)}; \quad T_W = K_0(T_{sold} + H_m/C_{pl})$$
(14)

where U is specific heat, C_e is f.e.m. division coefficient, η is heat discipated coefficient from the specified elements and T is time constant, $0 \le K_0 \le 1$.

The M-effect time
$$t_m = Z^2/N_D \cdot D$$
 (15)

where N_D is the distribution coefficient, Z is the element thickness and D is the diffusion coefficient. If $\mathcal{V}=(T_{\text{Sold}}+H_{\text{m}}/C_{\text{Dl}})$, it is said that the melted M-spots will flow along the element to the neck and cause the rupture of the fuse element due to M-effect.

6. APPLICATIONS

The programs in f.e.m. and the formula (14), (15) have been used to simulate the prearcing phenomena of a type of full range fuses and got some successful results given in figures (from Fig. 3 to Fig. 10), the element of which is shown in Fig. 1 (A). The fuse rated current and voltage are respectively 63A and 500W For different shapes of elements, the parameters needed to be changed are the f.e.m. division grid and physical data of the fuse-element, so it is very convinient for users and designers to use this method to simulate.

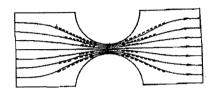


Fig. 3 Current flow distribution

—— Distribution in cold state

—— Distribution in hot state

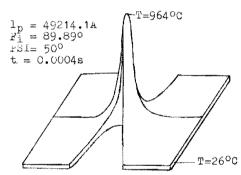


Fig. 4 Temperature field with short circuit current

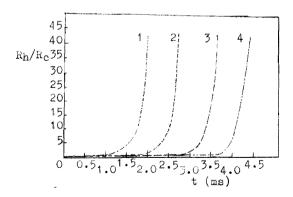


Fig. 5 Hot state R_h/Cold state R_c VS time Curve 1 $I_p = 5001.33A$, $\phi = 88.78^\circ$, $\psi = 67^\circ$ Curve 2 $I_p = 3889.69A$, $\phi = 88.79^\circ$, $\psi = 60^\circ$ Curve 3 $I_p = 2500,67A$, $\phi = 88.96^\circ$, $\psi = 47^\circ$ Curve 4 $I_p = 1750.57A$, $\phi = 89.16^\circ$, $\psi = 47^\circ$

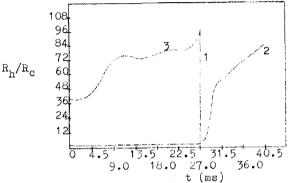


Fig. 6 Hot state R_h/Cold state R_c VS time $I_p = 580.32\text{A}, \ \psi = 83.94^{\circ}, \ \psi = 56^{\circ}$

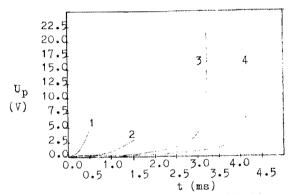


Fig. 7 Prearcing voltage VS time Curve 1 I_p = 50021.5A, ψ =89.89°, ψ = 67° Curve 2 I_p = 8753.50A, ψ =89.91°, ψ = 60° Curve 3 I_p = 3070.92A, ψ =88.82°, ψ = 40° Gurve 4 I_p = 1750.57A, ψ =89.16°, ψ = 47°

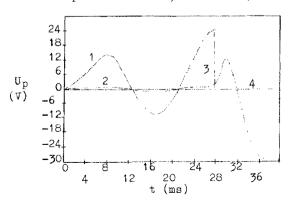
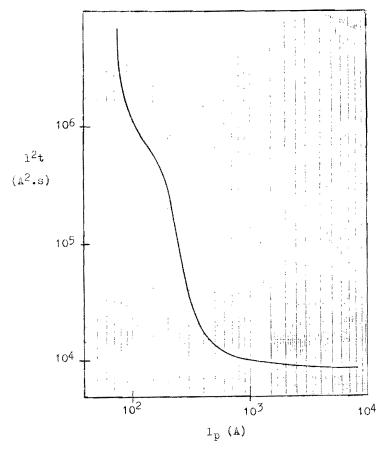


Fig. 8 Prearcing voltage VS Time $l_p = 580.32 \text{A}, \quad \psi = 83.94^{\circ}, \quad \dot{\psi} = 56^{\circ}$



rig. 9 12t - Ip characteristic

7. <u>#13063810m</u>

Fig. 2 is suitable for current fields and temperature fields of the fuse-element on principle, in oder to reduce the CPU time, small time steps at are taken to solve the two set of

equations respectively for compensation.

It will be seen from Fig. 3 that the current flowing through element is concentrated towards the edge with time, especially in the constrictions. The reason for which is that the temperature in this region is lower than that in the middle of the element, so the resistantivity in the middle is greater.

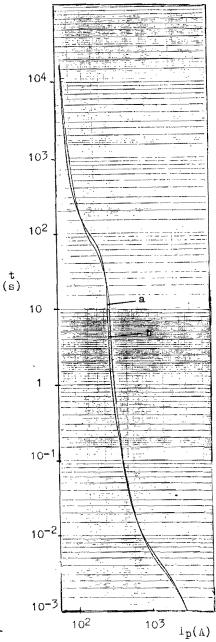
Tig. 5 and Fig. 6 prove that the larger the prospective current, the smaller the time when the ratio of the heat resistance to the cold resistance begins to increase extremely. In other words, the prearcing time is smaller for a larger prospective current. The similar cases exist in the variation of the pre-arcing voltage shown in Fig. 7 and Fig.8.

variation of the pre-arcing voltage shown in Fig. 7 and Fig.8. b. test results In the breaking tests of low overload currents several changes of pre-arcing voltage are observed by the indicator, before Fig.10 t—I characteristic elements melt. There are three times of the voltage increase, this is a indirect evidence of the calculation results. I²t-Ip characteristic of the single element is given in Fig. 9. While Ip > 3000A, the value of 1²t is kept constant, nearly having nothing to do with Ip, when Ip < 1000A, the value of 1²t increases rapidly as the prospective current Ip decreases, at the heighbour of 180A, as Ip decreases the value increases slowly, as Ip approaches 1.25In, the value increases rapidly too. It is considered that M_effect has great influence in the range of 1.25In to 180A, when Iphas the lowest value, which is near the MFC, therefore 1²t has a large value, the heat conduction of element is in action from 2000A to 2000A, however, for the large prospective current (Ip > 3000A), the adiabatic process is under control.

is under control. The comparasion has been made in Fig. 10 between the theoretical curve and tested results. It proves that the deviation between the two is small and the calculation results are helpful for future test.

8. CONCLUSION

The method above may be used to simulate the pre-arcing phenomena of the fuse-element and the acceptable accuracy is achieved in calculation and good correlation is obtained between calculated and measured values of cold resistances and t-I characteristics. Therefore the method could be used in CAD of fuses.



theoretical curve

test results

LIST OF PRINCIPAL SYMBOLS

```
conduction coefficient;
                                                     IE
                                                            division number:
K_{\mathbf{X}}, K_{\mathbf{v}}, K
       damped coefficient;
                                                            mass density, resistantivity;
\kappa_{t}
                                                      6
                                                            thermal capacity, specific heat;
       potential function;
                                                     C
                                                     μ
ø
       derivative of potential function;
                                                            surfacial heat discipated coefficient;
                                                     Ce
                                                            f.e.m. division coefficient;
Ω
       calculation region;
                                                            heat discipated coefficient from the specified elements to tags and end caps.
Ni
       shape function;
       electric conductivity;
E
       electric field strength;
J
       current density;
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APPENDIX

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PHYSICAL DATA FOR COPPER
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resistantivity at the room temperature 1.6961x10-6 n.cm;
                                                                21.3x10^{-6} \Omega.cm;
      resistantivity in liquid phase at melting point
e01
                                               0.0045 °C-1:
      resistance temperature coefficient
d
T_{\rm m}
      melting point
                          1084.5 °C;
      melting latent heat
                                211.4 J.g-1;
T_{\mathbf{a}}
      vaporization temperature
      vaporization latent heat
                                   4752.16 J.g<sup>-1</sup>
İιΑ
      thermal conductivity 4.01 \text{ w.cm}^{-1.0}\text{C}^{-1};
K
                  8.93 g.cm<sup>-3</sup>:
      density
      specific heat in solid state 0.385 w.s.g-1.0c-1.
PHYSICAL DATA FOR M-SPOTS
                          227-231.9 °C;
Tsold melting point
      melting latent heat 60.66 J.g-1.
OTHER DATA
K_0 = 0.9, T = 1089, I_c = 73A, D = 10^{-4} - 10^{-6} cm<sup>2</sup>·s<sup>-1</sup>.
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